

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/701,332	)	
		)	
Filed:	November 4, 2003	)	Conf. No.: 5874
		)	
Title:	<b>A Novel BISR Mode to Test the Redundant Elements and Regular Functional Memory to Avoid Test Escapes</b>	)	
		)	
Inventor:	Ghasi R. Agrawal et al.	)	
		)	
Art Unit:	2117	)	
		)	
Examiner:	Steve N. Nguyen	)	
		)	
Atty. Ref:	03-1343	)	

**RESPONSE TO THE OFFICE ACTION MAILED NOVEMBER 21, 2008**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed November 21, 2008, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.

DO NOT ENTER: /SN/